



CMS ECAL Trigger Primitives: Tests of the boards

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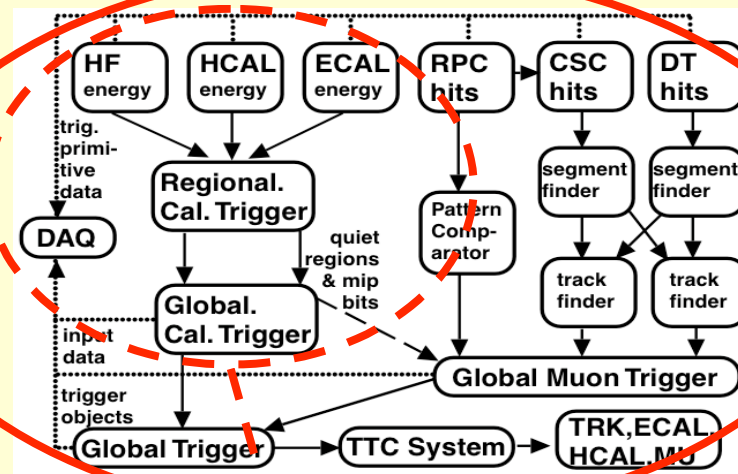
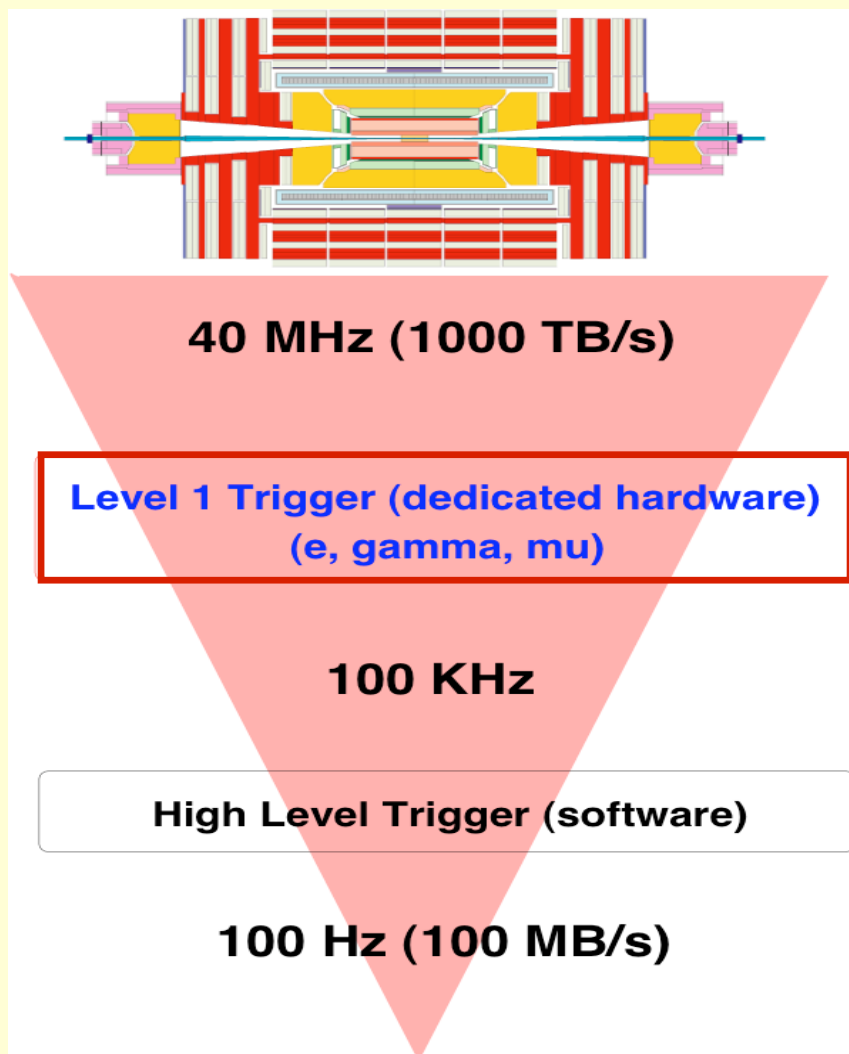
Outline



- Overview of the ECAL Trigger Primitives
- The Front-End board
 - Brief overview
 - XFEST: the eXtended Front-End System Test
- The Trigger Concentrator Card
 - Brief overview
 - TCC24: the prototype
 - Tests of the TCC24
 - Test bench for production



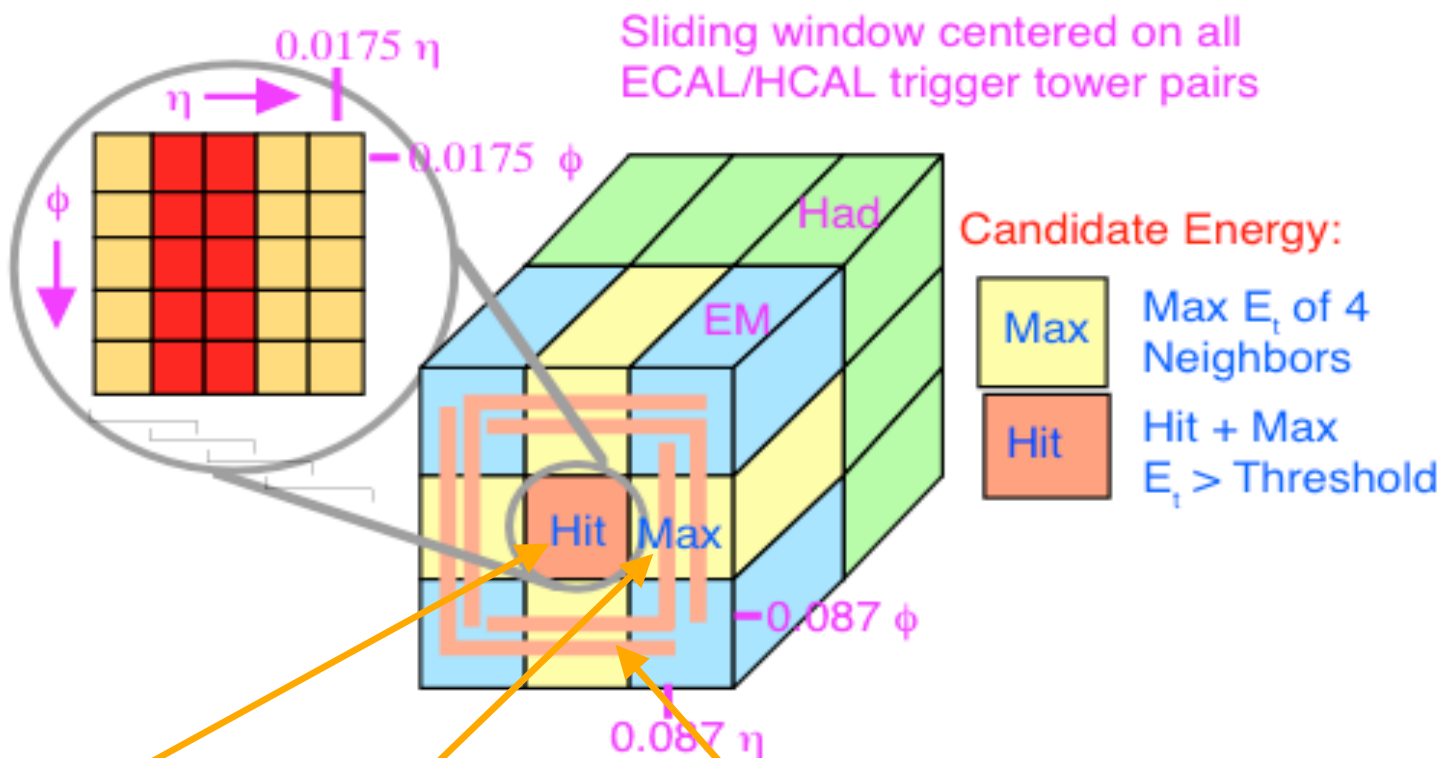
The ECAL Trigger Primitives



- ECAL Trigger Primitive (TP) 40 MHz pipeline :**
- 8 bits: Energy sums of a trigger tower + Bunch crossing assignment
 - 1 bit: ECAL Fine Grain bit



The ECAL Trigger Primitives and e/γ trigger



Electron:

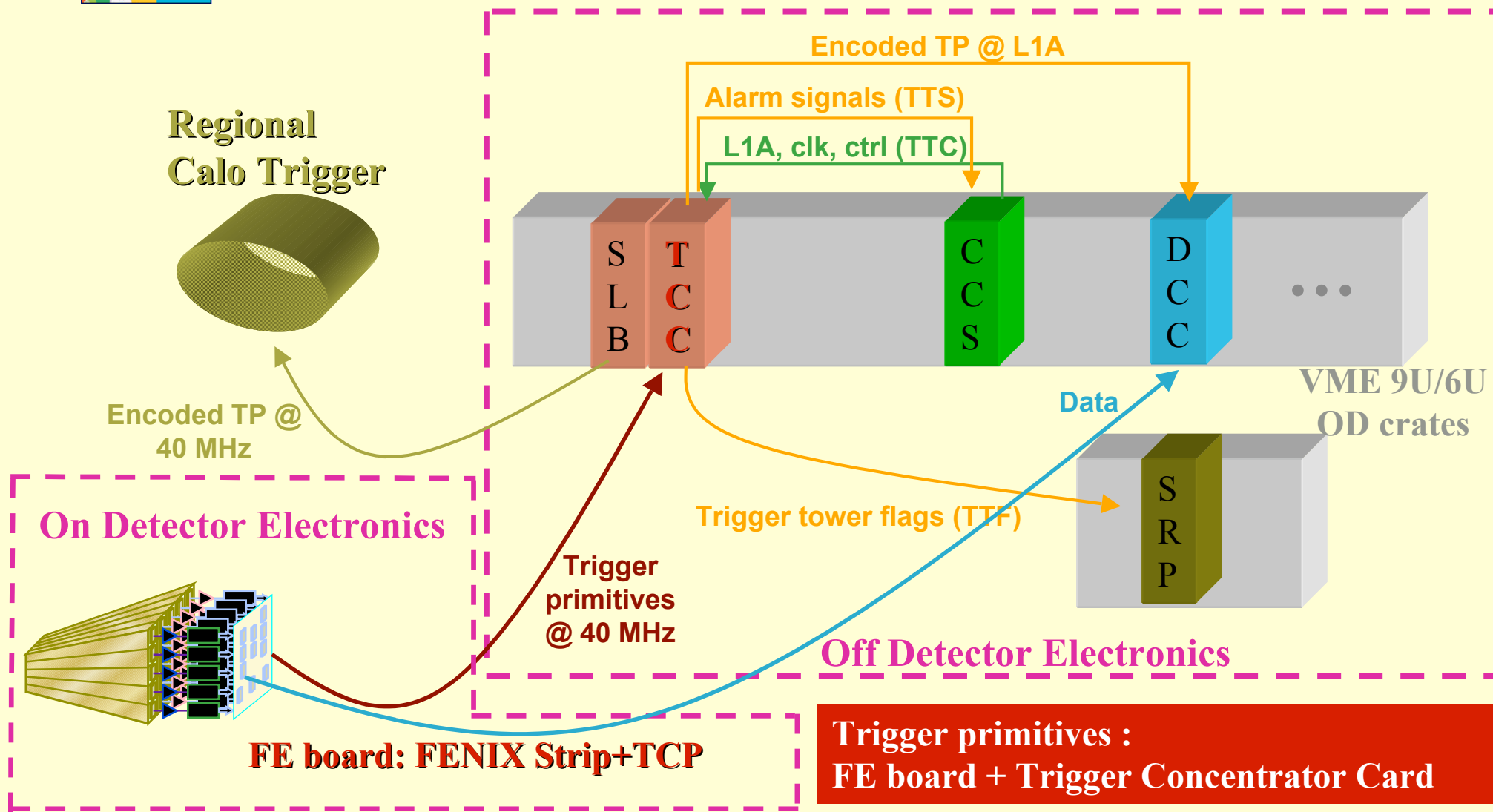
1. E_T "Hit tower" + "Max tower" > threshold
2. Fine Grain (FG) veto: highest energy adjacent strip pair \approx large fraction of total (e.g. 90%)
3. H/E veto (e.g. 5%)

Isolated Electron:

1. 8 neighbours towers with FG veto and H/E veto
2. 1 group of 5 "corner towers" with $E_T < \text{threshold}$



The ECAL Trigger Primitives Path





The Front End Board



Brief overview of the Front End board



- The FE board:

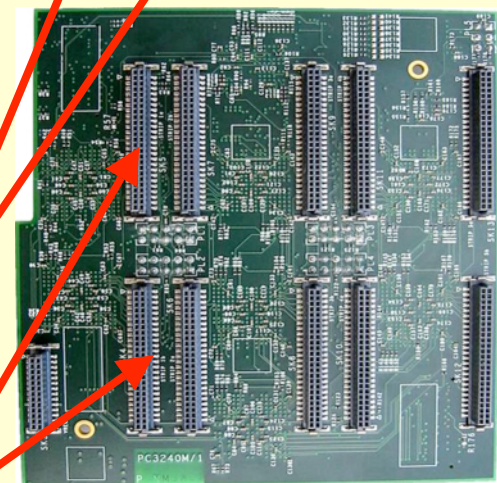
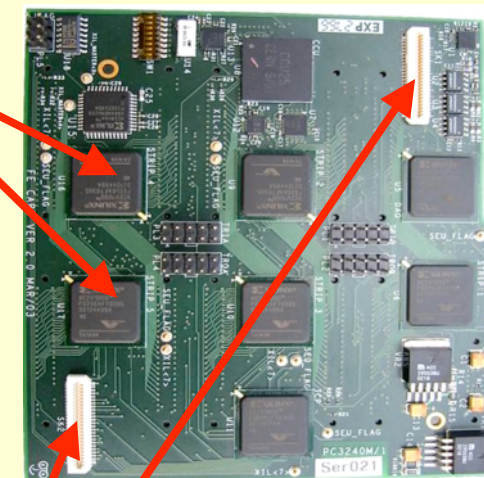
- receives signals from a trigger tower (25 crystals of 5 VFE)
- stores the data during the L1 latency
- performs the Trigger Primitive calculations
- formats and sends the data (via GOH: Giga Optolink Hybrid) to the DAQ (DCC board) when L1 accept signal.
- sends the Trigger Primitives to the TCC @40 MHz (via GOH)

For details, see M. Gastal's talk

FENIX chips

GOH connectors

VFE connectors



10 cm



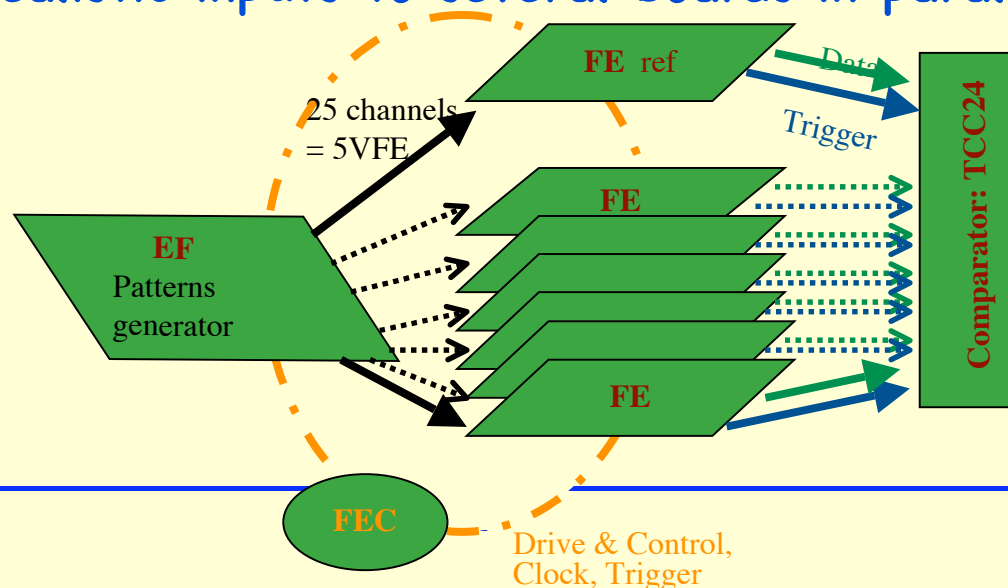
XFEST: eXtended Front-End System Test



XFEST: System Test for FE board production

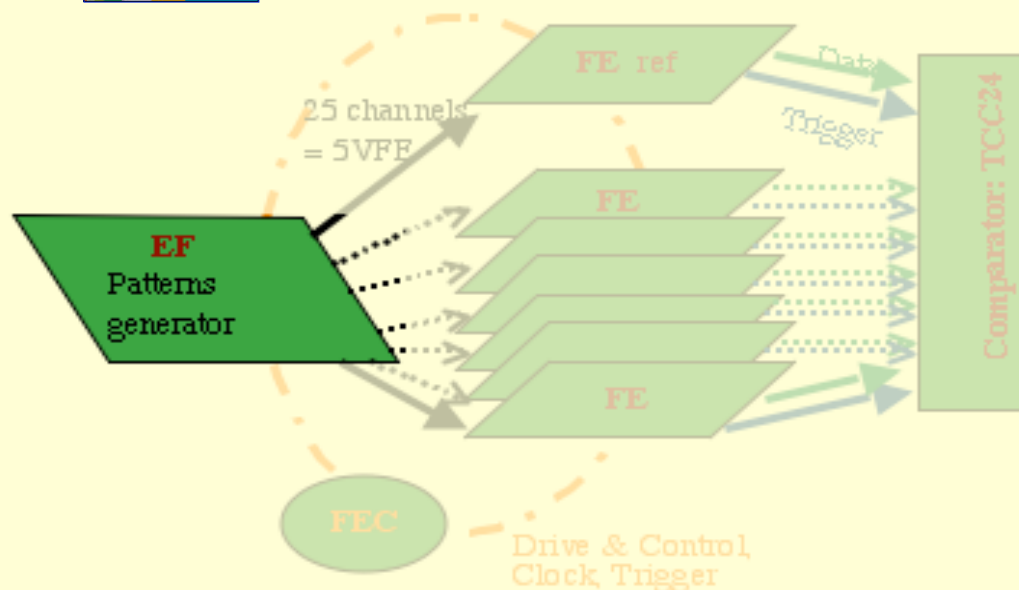
- 3200 boards to be tested, 80/week until mid-2005
 1. **Short tests:** just after burn in to reject quickly dead boards (see M. Gastal's talk)
 2. **XFEST:** Long tests (several hours) with lots of patterns
- **1 FE board :** inputs 25×16 bits @ 40 MHz, outputs 2×800 Mbits/s \Rightarrow impossible to cover all patterns in a reasonable time
- **Idea:** inject same realistic inputs to several boards in parallel

Basic Synoptic :





XFEST: 1) Pattern Generator

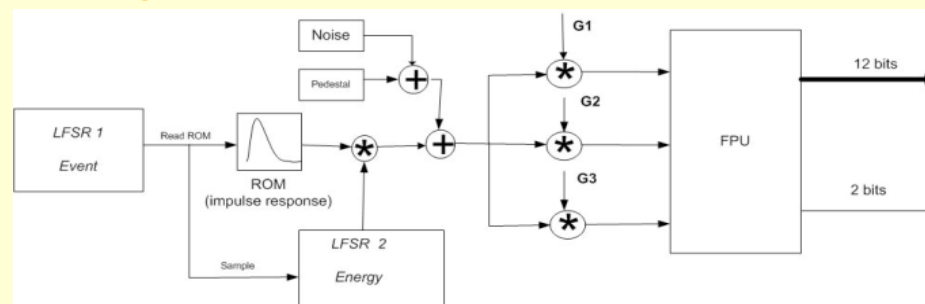


Use a FE itself: FE → EF



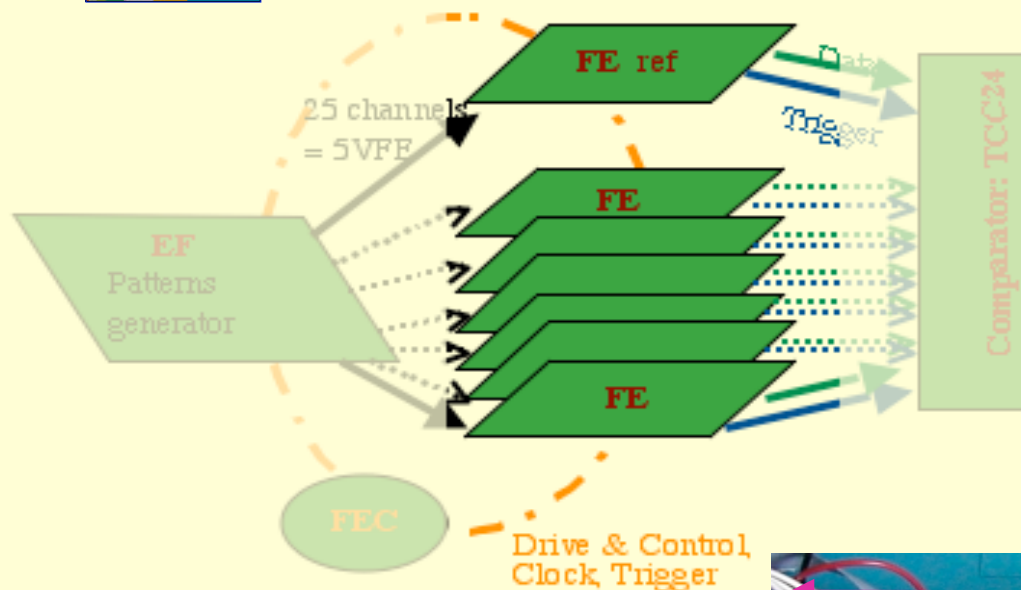
EF = FE prototype with FPGAs + FPGA reprogramming:

- Emulates signals from VFE:
 - MGPA multigain
 - Random noise using LFSR (40 bits)
 - Variable signal amplitude using LFSR
- Allows loading of different signal shape
- Allows superposition of signals to mimic pile-up





XFEST: 2) Mother board



Mother board:

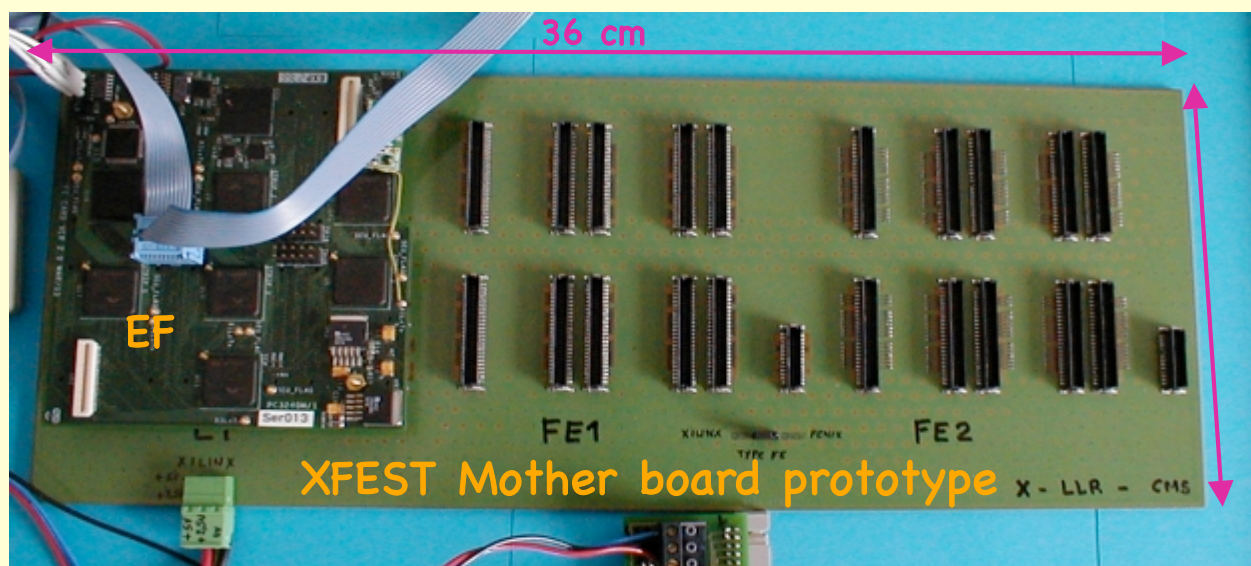
- Connect EF to several FE
- Power supply

Realisation of a prototype:

- EF + 2 FE
- 24 layers
- PCB class 6, 4.8 mm

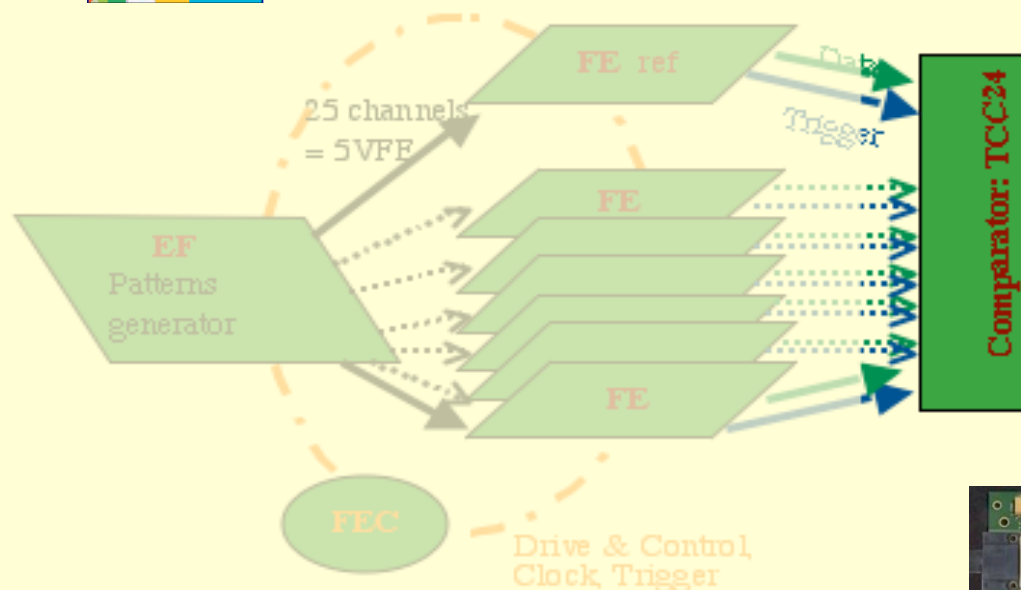
Final version:

- EF + 4 FE
- Strong constraints to avoid cross-talk and caution on timing of signals \Rightarrow 400 traces with characteristic impedance 50Ω
- PCB class 6, 4.8mm, 48cm x 35cm
- Expected by october





XFEST: 3) Comparator: TCC24



⇒ Use VME6U TCC24 prototype
(see later on for details)

Reprogramming allows:

- comparison of an input signal (1 FE) to other inputs
- If discrepancy, send channels in error to VME

In CMS:

- FE trigger → TCC board
- FE Data → DCC board

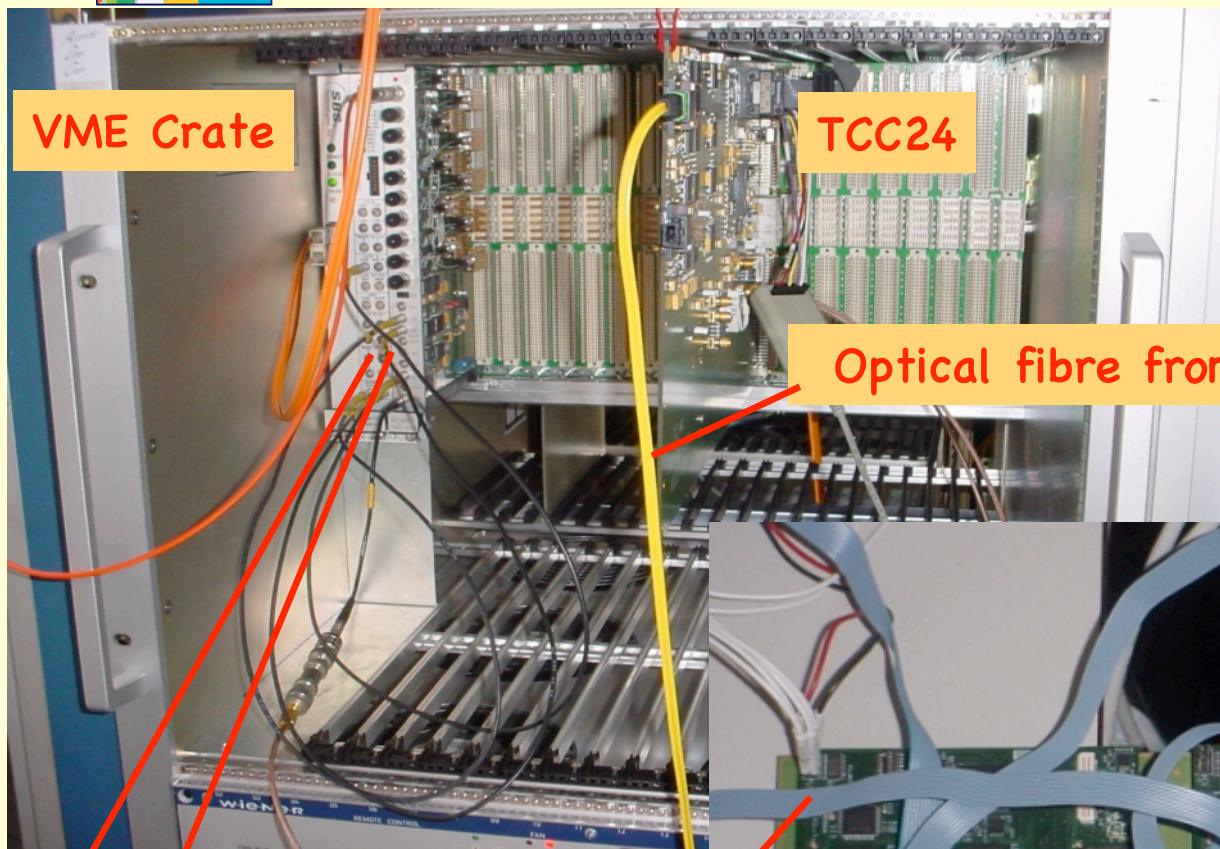
In XFEST:

- FE trigger+Data → TCC board
⇒ need reprogramming of TCC





XFEST SetUp



VME Crate

TCC24

Optical fibre from FE

Test bench controlled by a single PC running linux:

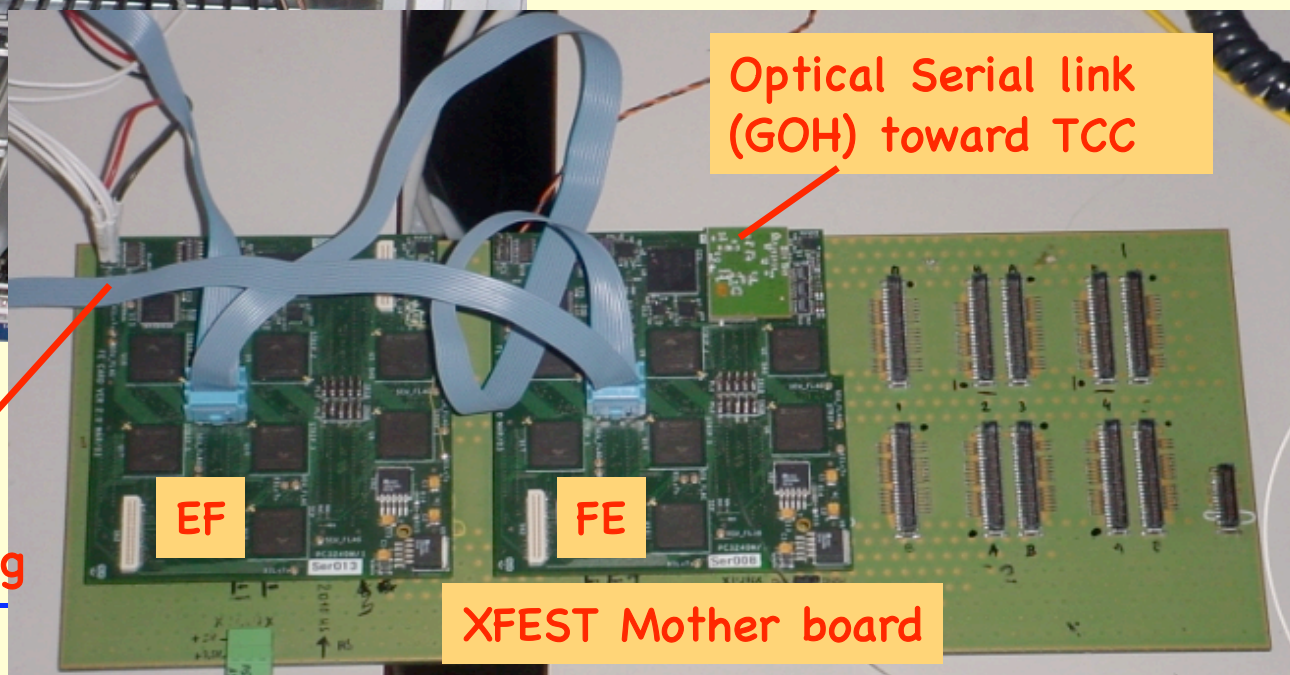
VME crate via XDAQ/HAL environment, FEC (token ring), RS232, GUI

TTCvi/: clock, trigger (elec.)

TTCex : elec. → opt.

FEC (PCI) → Token Ring

LECC2004, sept 14, 2004



Optical Serial link (GOH) toward TCC

EF

FE

XFEST Mother board



The Trigger Concentrator Card



Brief overview of the Trigger Concentrator Card (TCC)



TCC Functions :

- Receives and **deserializes** the (optical) data from FE
- Finalises and **encodes** the Trigger Primitive (TP) using a non-linear scale for the total transverse energy
- **Sends** the encoded TP @ 40 MHz to the regional trigger through SLB (assuring time alignment between channels, see N. Almeida talk tomorrow)
- **Stores** the encoded TP during L1 latency and transmits it to DCC when L1A
- Computes TTF (= Trigger Tower Flags): **Classifies** trigger towers into high/medium/low interest and sends it to SRP when L1A

TCC in numbers (barrel version) :

- double width **VME 9U** module managing **72** channels (=68 trigger towers + 4 not used) \Rightarrow 1 whole supermodule
- Basic Components : **6** NGKs (O/E receivers 12 channels), **72** Agilent (deserializer) and **8** FPGAs (**6** Xilinx virtex2, **1** Xilinx virtex2 pro, **1** Altera) + **9** SLBs boards
- Latency must be \leq **7** Clocks \Rightarrow imposes Agilent choice with protocol **CIMT** (2.5 clocks)

PCB 10 layers
Class 6 (120 μm)

NGK

Very high density :
use micro-Vias (120 μm drilled by laser) and BGA components

Agilent on both side

Rapid Signal traces with characteristic impedance 50/100 Ω

Xilinx BGA

SLB connectors

3 layers shown

1 4 10

L.Z / Y.B / M.B

COMET-2015-04

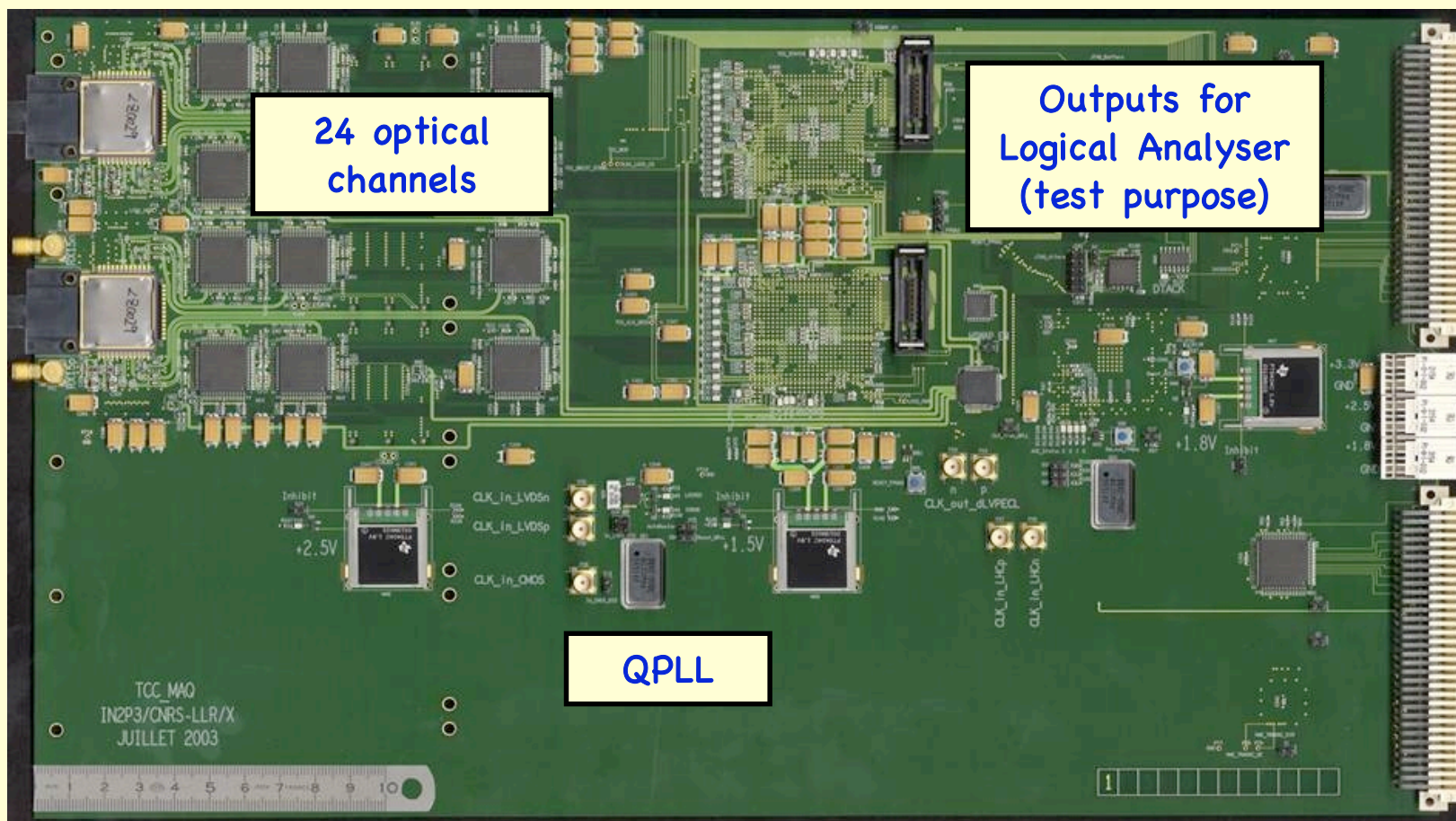


TCC24: Prototype top view



Aims : validate the design/implementation: Agilent deserializers, μ -vias, BGA

TCC24 : VME 6U board, 24 channels 1/3 of final version



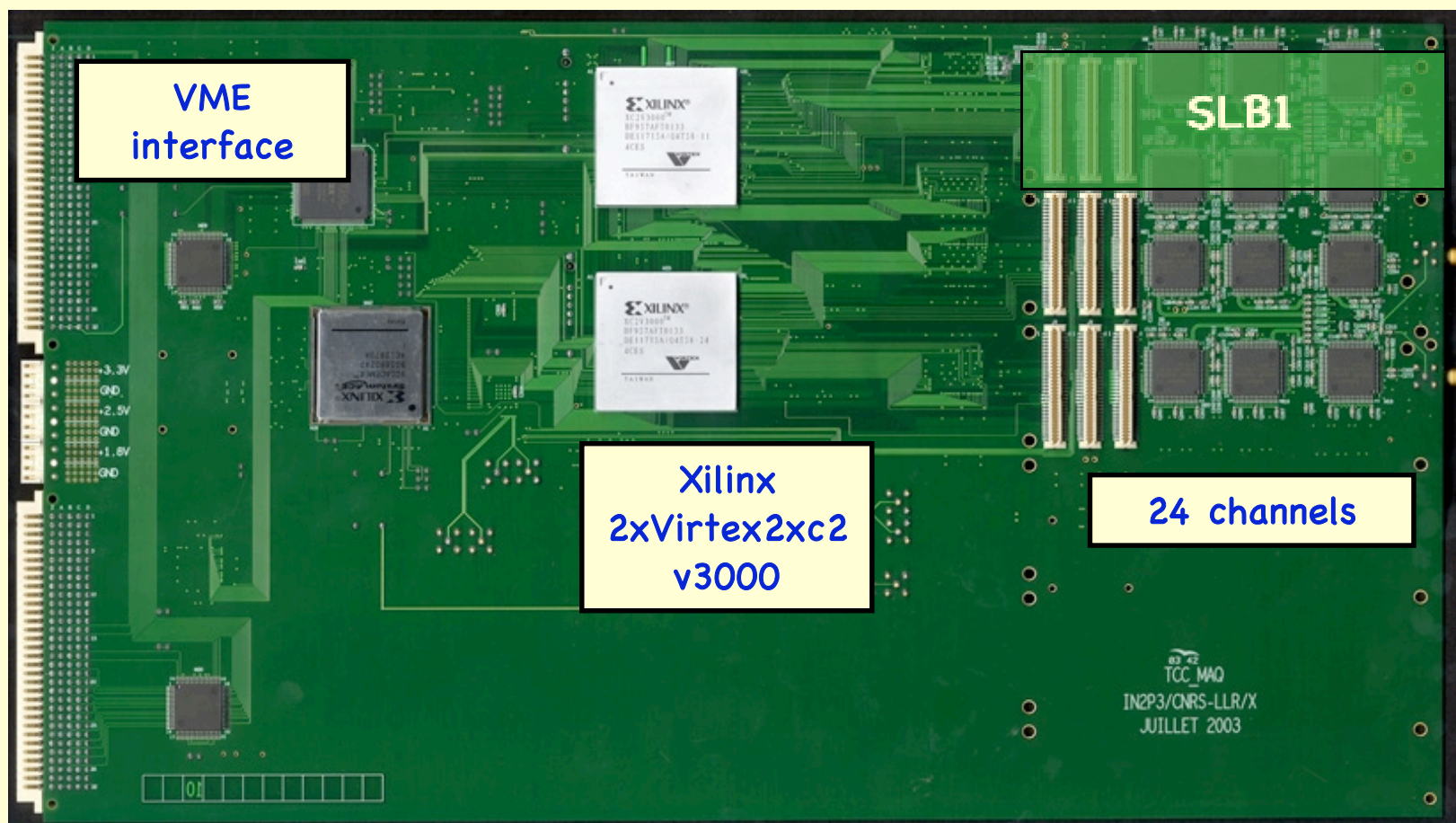


TCC24: Prototype bottom view



Aims : validate the design/implementation: Agilent deserializers, μ -vias, BGA

TCC24 : VME 6U board, 24 channels 1/3 of final version





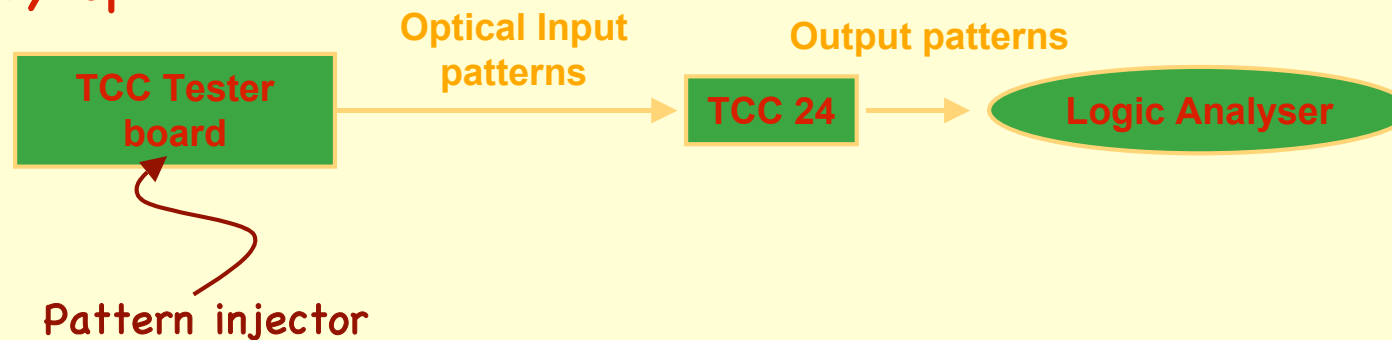
Tests of TCC24



Tests performed :

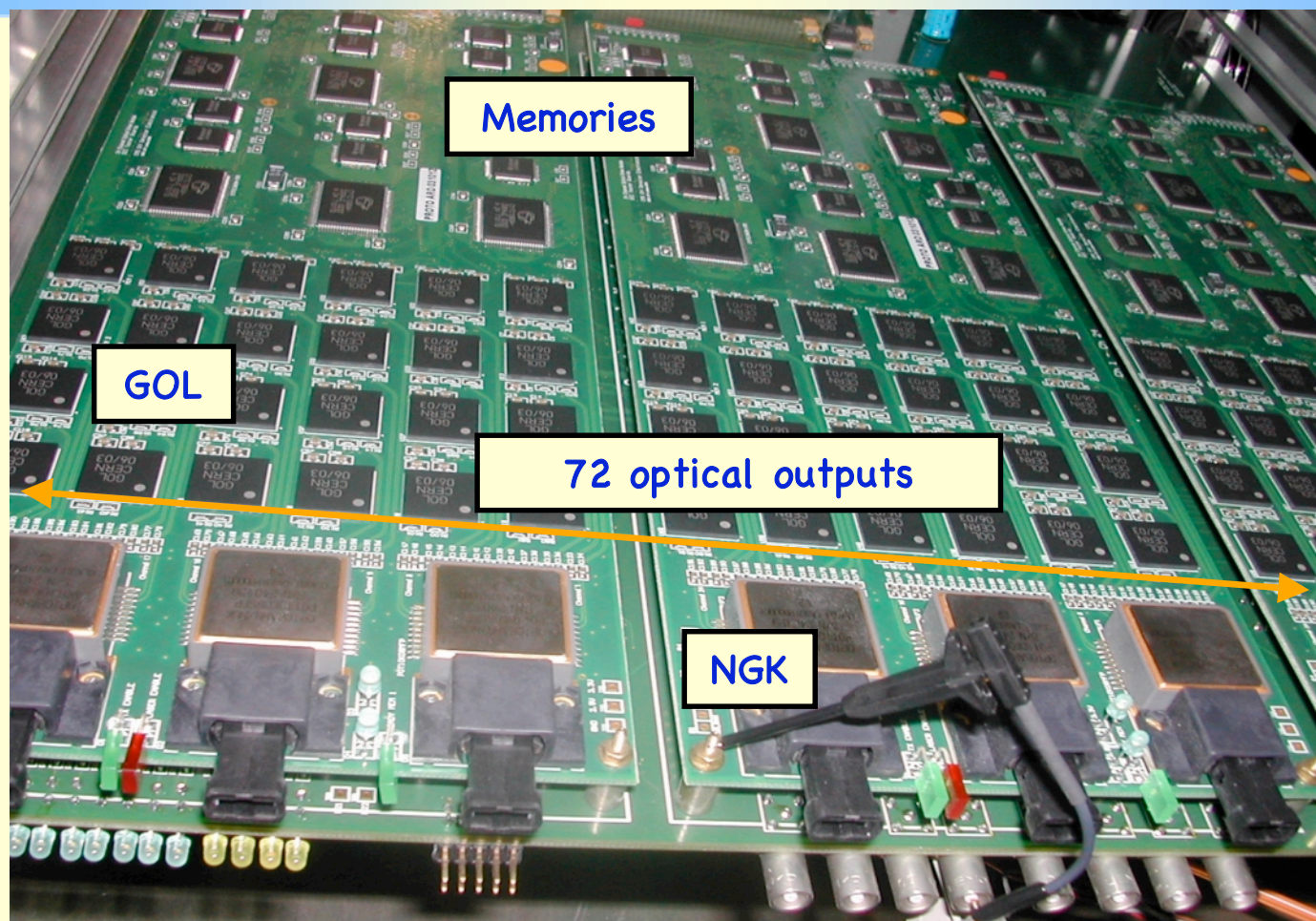
1. Power consumption measurement (*not shown in this talk*)
2. Latency measurements (*not shown in this talk*) : ≤ 6 clock unit ($<$ requirement)
3. Bit Error Rate measurements
 1. Direct measurement
 2. Indirect measurements :
 1. Eye diagram
 2. Jitter

Basic Synoptic :





Tests of TCC24: TCCTester board

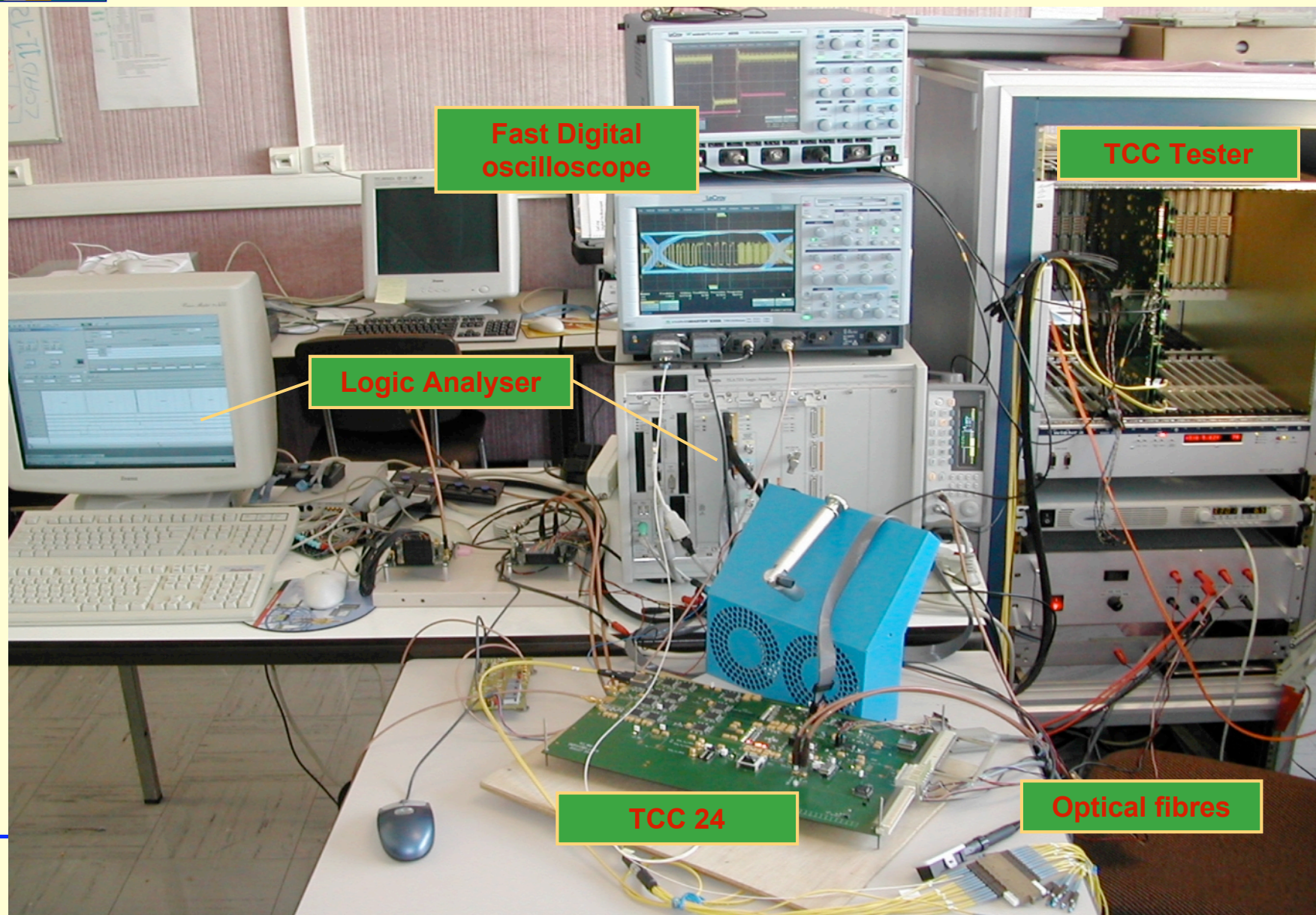


TCC Tester
will be used
for
production
test bench

- TCC Tester = clone of the DCC Tester (see J. C. Da Silva talk for details)
- Able to transmit loaded pattern (in memories) @ 40 MHz

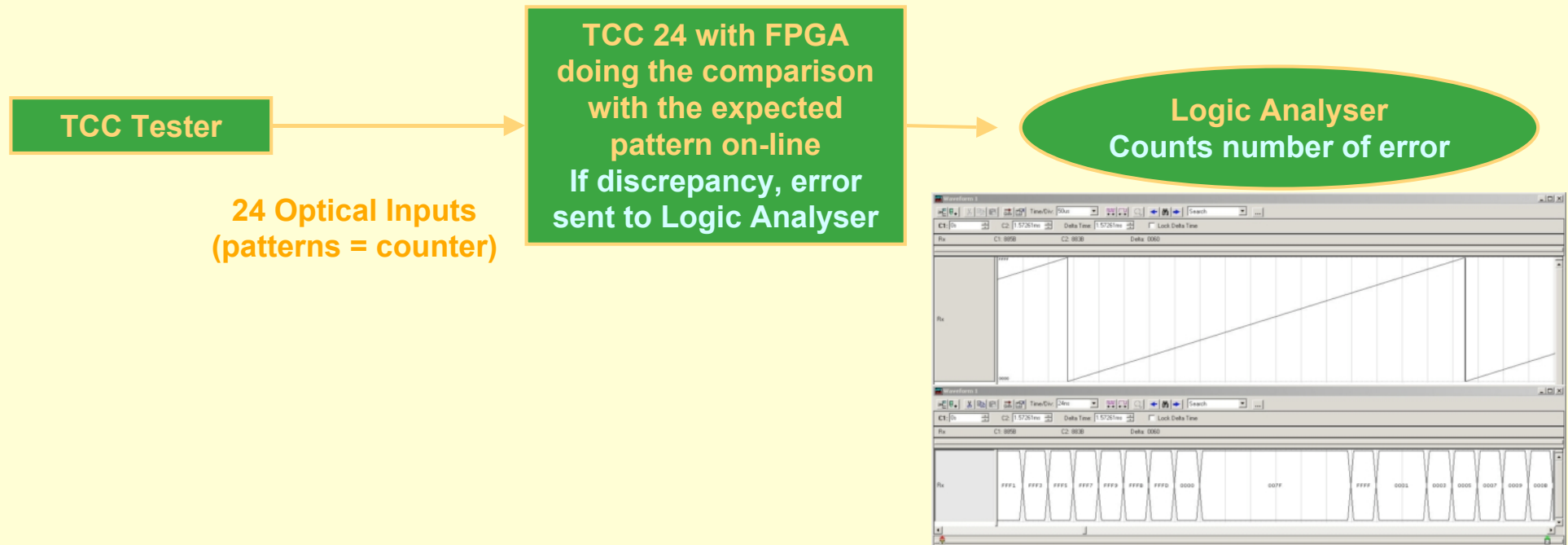


Tests of TCC24: setup





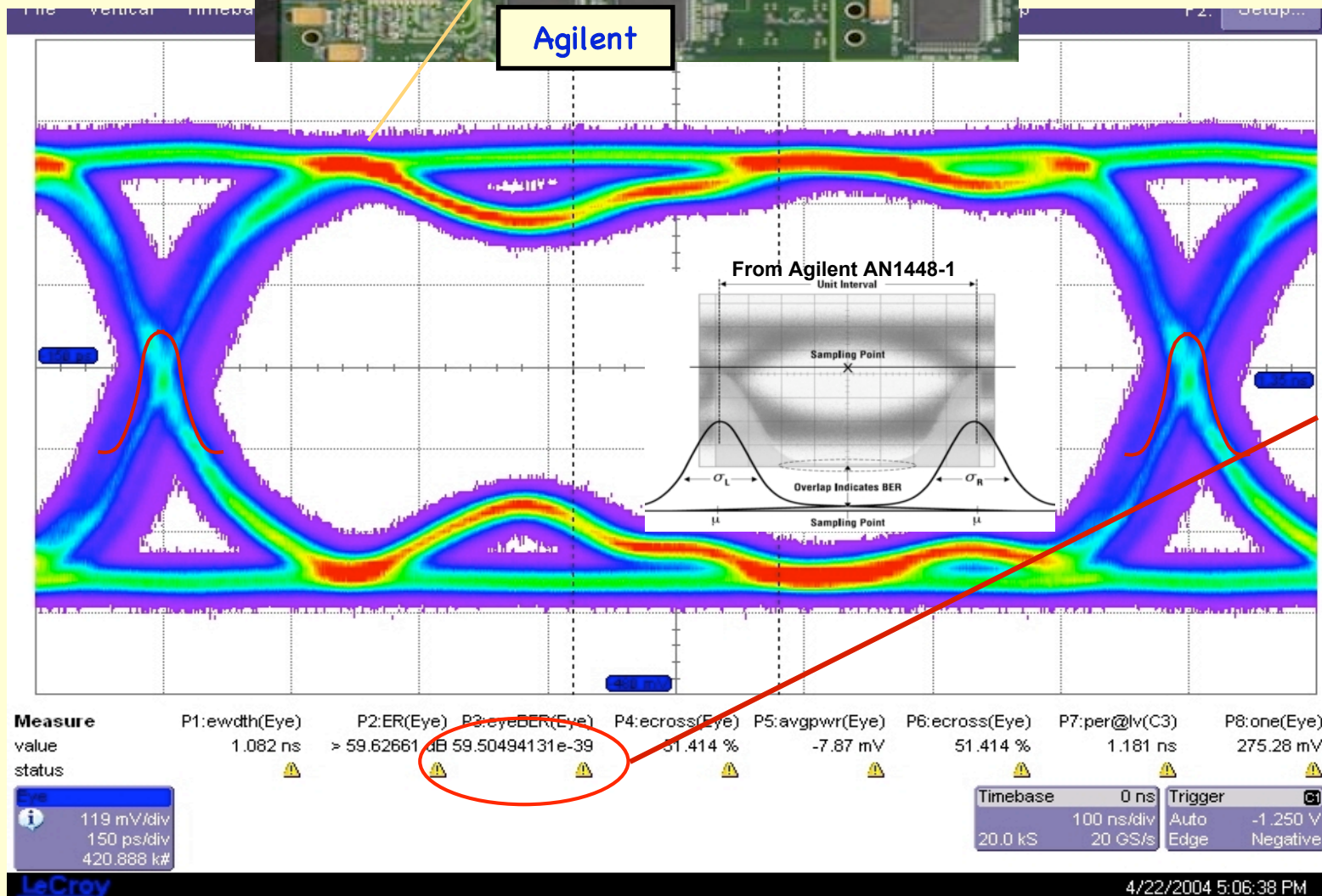
Tests of TCC24: BER direct measurement



1. Test continuously 1 channel during 145h (6 days) @ 40 MHz with 0 error
 $\Rightarrow \text{BER} < 3 \cdot 10^{-15} \Rightarrow$ less than 1 error every 1'35" in CMS
2. Test 18 channels (/24) in parallel (same pattern injected in every channel): no error during 16h10' @ 40 MHz $\Rightarrow \text{BER} < 2 \cdot 10^{-14}$



Tests of TCC24: BER and Eye diagram



Eye wide open

Can expect very low BER !

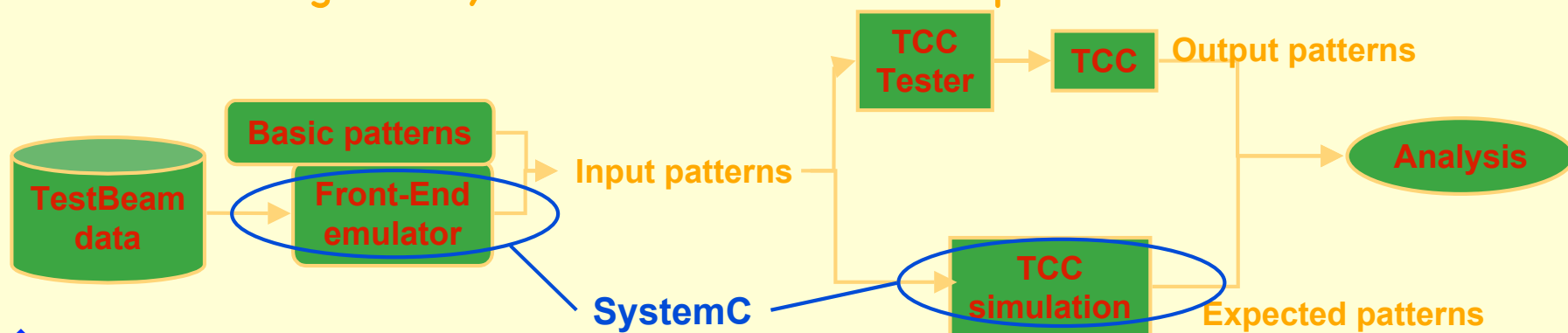


TCC Tests for production



First TCC barrel in october 2004, pre-production beginning of 2005,
42 boards (barrel version) to produce/test in second half of 2005

1. JTAG for boundary scan (up to SLB boards)
2. Built-in self test \Rightarrow check firmware:
 1. patterns auto generated by TCC
 2. Comparison to expected data in ROM
3. Short tests (fraction of seconds @40 MHz):
 1. Inject patterns (coming from testbeam, counter etc)
 2. Compare output to SystemC simulation (detailed hardware simulation, see <http://www.systemc.org> for details) \Rightarrow Uses Logic Analyser to read out/store output data





TCC Tests for production



4. Long tests (several hours/days):

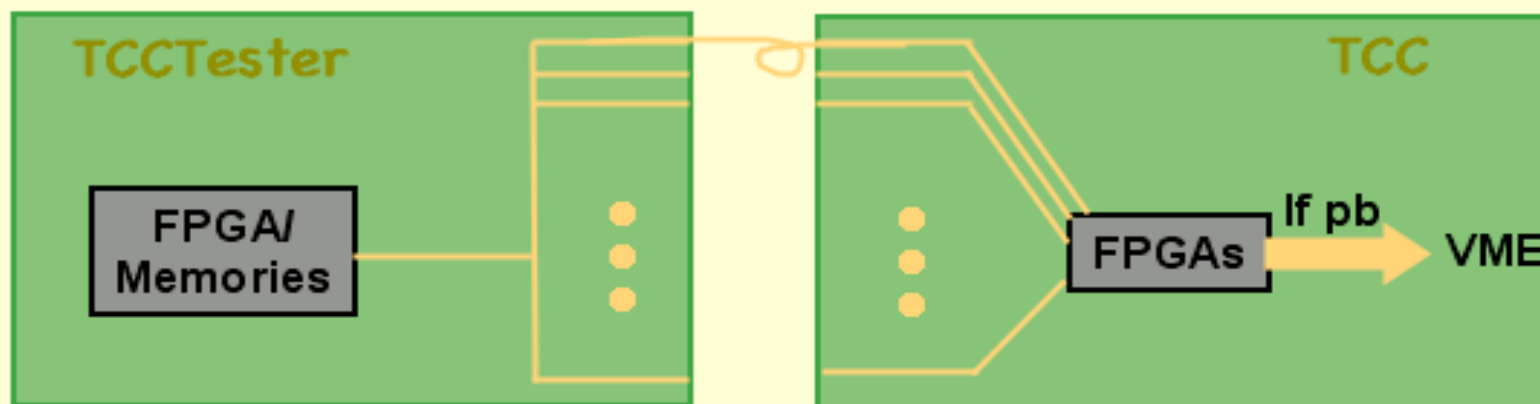
1. Inject

1. pseudo-random patterns auto generated by TCCTester
2. patterns loaded in TCCTester memories

2. Same patterns injected in all channels

3. Compare outputs in TCC FPGA itself

4. Readout/store data only if discrepancy via VME





Conclusion



- Trigger Primitive are generated using 2 boards:
 - Front End board
 - Trigger Concentrator Card
- Both boards need test bench to validate the up-coming production
- Coherent test benches have been developed using same approach (XDAQ/HAL environment for VME, SystemC etc...) and even same hardware if possible



Back-up slides

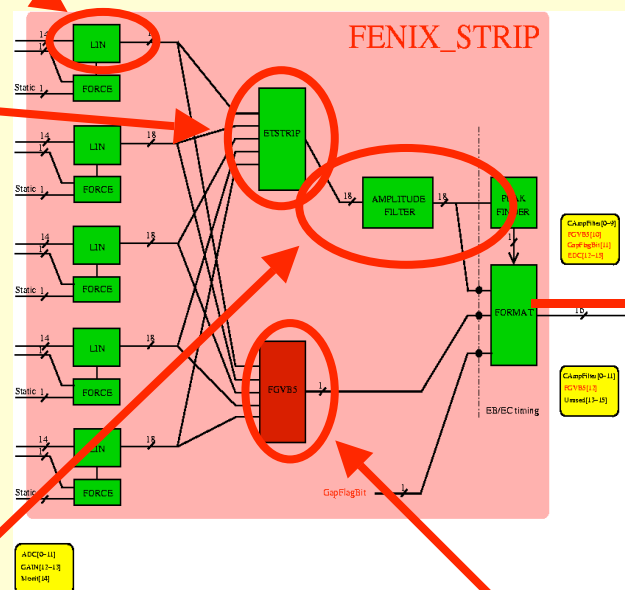


FENIX block diagram for Trigger Primitives



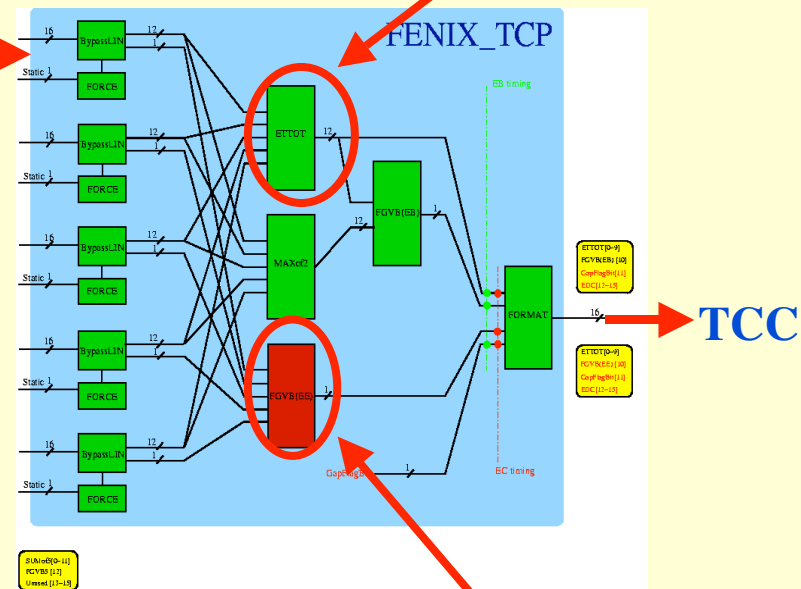
linearization
from 12+2 to 18

strip or
pseudo
strip
signal



BCID FIR filter + Peak Finder

Fine Grain Veto Bit



total E_T

► **TCC**

Fine Grain Veto Bit



Tests of TCC24: Latency 1.

LM

GOL
TCC Tester

NGK Tx

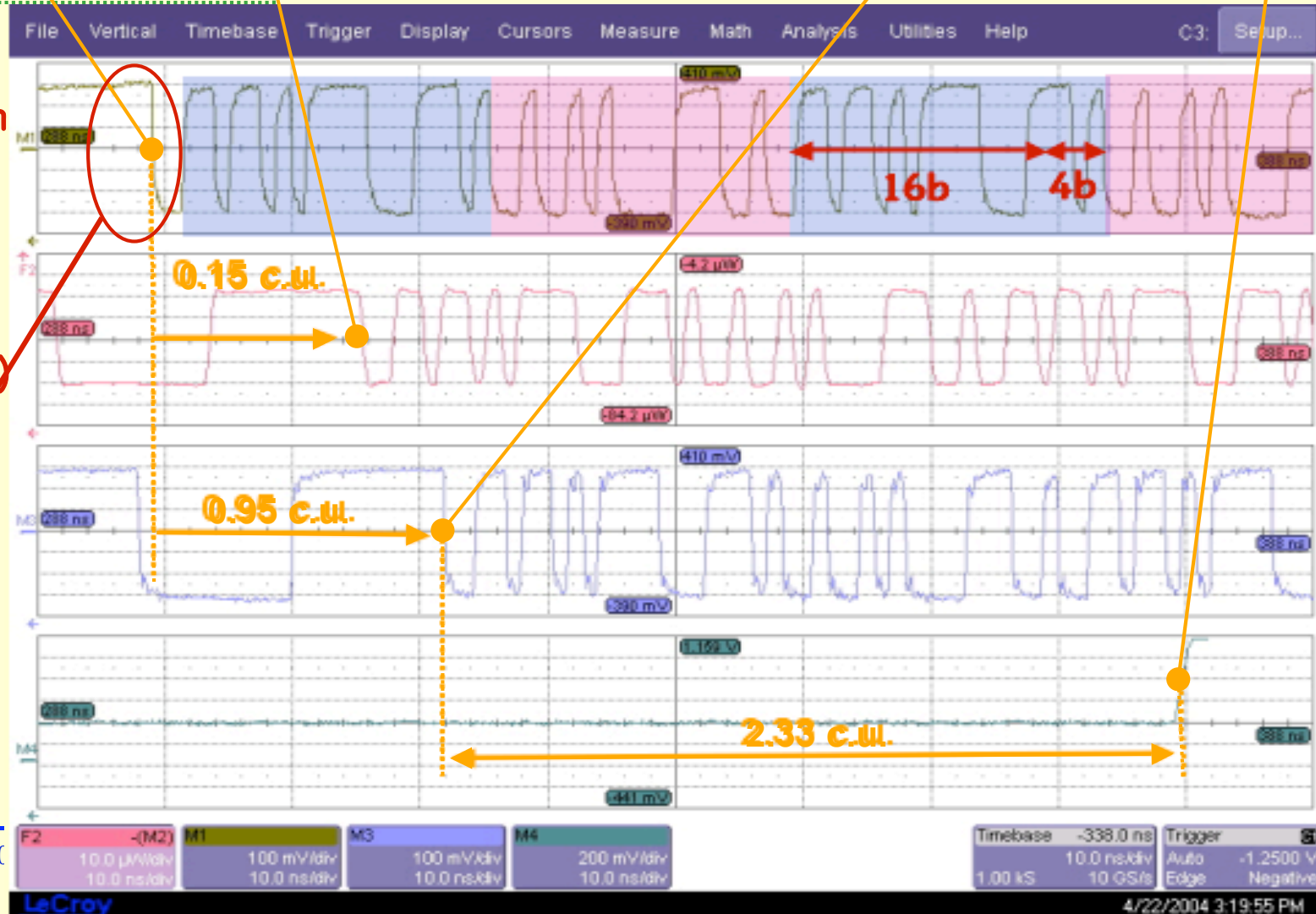
NGK Rx

Agilent
TCC 24

FPGA

Signal clean
⇒ Able to
decode the
word (8FB5
and 8FB5,
LSB on left)

Master
transition
(CIMT): 1100

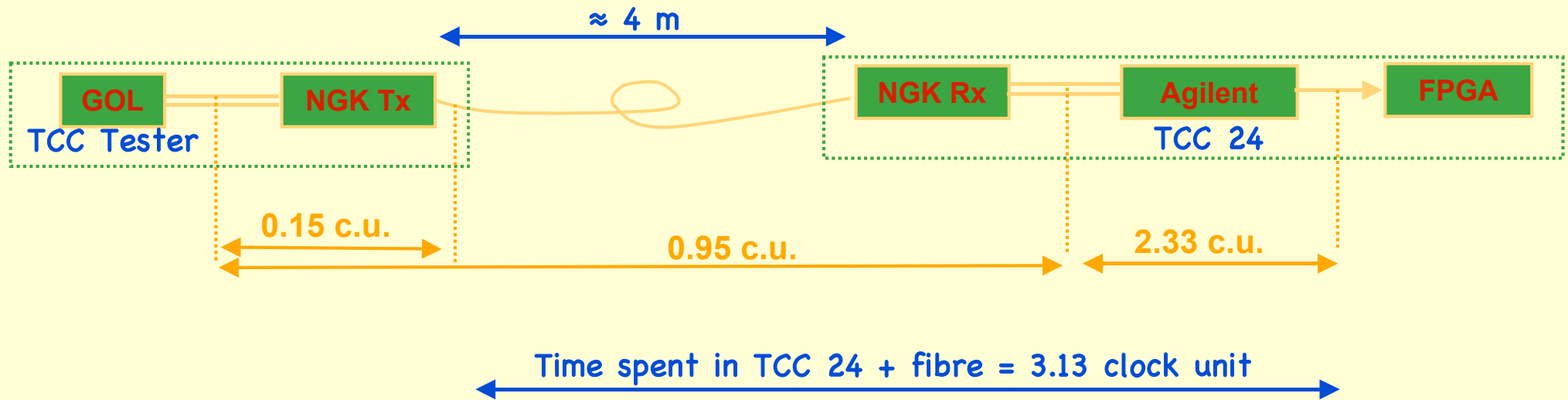


LECC20

28



Tests of TCC24: Latency 2.



Latency: considering 2 c.u in FPGA + alignment $\Rightarrow \leq 6$ clock unit
($<$ requirement)